

## KBr Crystal: Cleaved in Air

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# KBr Crystal: Cleaved in Air

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A crystal of infrared-grade potassium bromide (KBr) was cleaved in air using a clean single-edged razor blade. The crystal was adhered to double-sided adhesive tape and analyzed by XPS at an angle that maximizes the information associated with subsurface bulk. The crystal's dimensions were 3 mm × 3 mm × 10 mm ( $w \times h \times l$ ), and only the freshly exposed surface was analyzed. A mesh made of nickel wire was placed about 1 mm above the surface of the sample to flatten the electric fields on the sample.

**Keywords:** XPS; K; Br; crystal; nonconductive; insulator

**PACS:** 79.60.Eg, 82.80.Pv

**Accession #:** 00046

**Technique:** XPS

**Host Material:** KBr

**Instrument:** Surface Science  
Instruments X-Probe 206

**Major Elements in Spectrum:** K, Br

**Minor Elements in Spectrum:** C

**Printed Spectra:** 4

**Spectra in Electronic Record:** 4

**Spectral Category:** comparison

## SPECIMEN DESCRIPTION

**Host Material:** KBr

**CAS Registry #:** 7758-02-3

**Host Material Characteristics:** homogeneous; solid; single crystal; dielectric; inorganic compound

**Chemical Name:** potassium bromide

**Source:** unknown

**Host Composition:** K, Br

**Form:** single crystal

**Lot #:** N/A

**Structure:** N/A

**History Significance:** N/A

**As Received Condition:** as grown, stored in closed bottle

**Analyzed Region:** freshly exposed "bulk" surface

**Ex Situ Preparation/Mounting:** The specimen was cleaved in air using a freshly cleaned single-edged razor blade, and mounted with double-sided adhesive tape. A charge control mesh was placed ~1 mm above surface.

**In Situ Preparation:** no treatments

**Pre-Analysis Beam Exposure:** kept in an analytical chamber at  $\sim 10^{-9}$  Torr for 17 h before analysis

**Charge Control:** An electron "flood" gun (~3 eV, 1 mA) at normal incidence, and a charge control metal (Ni) mesh at a 1 mm height from the sample surface were used to control charging.

**Temp. During Analysis:** 320 K

**Pressure During Analysis:**  $< 1.00 \times 10^{-6}$  Pa

## SPECTROMETER DESCRIPTION

**Manufacturer and Model:** Surface Science Instruments X-Probe 206

**Analyzer Type:** spherical sector

**Detector:** 128 channel

## INSTRUMENT PARAMETERS COMMON TO ALL SPECTRA

### ■ Spectrometer

**Analyzer Mode:** constant pass energy

**Throughput ( $T = E^N$ ):**  $N = -1$

**Excitation Source:** Al  $K_{\alpha}$  monochromatic

**Excitation Source Window:** 1  $\mu\text{m}$  Mylar

**Source Energy:** 1486.6 eV

**Analyzer Width at 1000 eV:** 2000  $\mu\text{m} \times 2000 \mu\text{m}$

**Signal Mode:** multichannel direct

**Simultaneous Channels:** 128

### ■ Geometry

**Incident Angle:** 20°

**Source to Analyzer Angle:** 71°

**Emission Angle:** 0°

**Specimen Azimuthal Angle:** 90°

**Acceptance Angle from Analyzer Axis:** 0°

**Analyzer Angular Acceptance Width:** 30° × 30° at 1000 eV

**Comments:** Sampling depth was maximized to provide data which represents subsurface bulk.

## DATA ANALYSIS METHOD

**Energy Scale Correction:** All peak energies were adjusted such that the adventitious hydrocarbon C (1s) BE equaled 285.0 eV.

**Peak Shape and Background Method:** A Shirley function was used to define the baseline of the background and Voigt peak shapes (80:20 Gaussian-Lorentzian) were used to define the shape of each peak. Peak area ratios were constrained to the theoretical values.

**Quantitation Method:** Peak areas were used to calculate atomic percentages. Relative sensitivity factors were calculated by modifying Scofield values according to the following equa-

tion:  $RSF(X\text{-Probe}) = RSF(\text{Scofield}, C=1.0) \times [(1487 - \text{observed BE}) / (1487 - 285)]^{1.0}$ , where 1.0 is an exponent. A 150 eV Pass Energy was used for data collection.

#### REFERENCES

1. J. H. Scofield, *J. Electron. Spectrosc. Relat. Phenom.* **8**, 129 (1976).

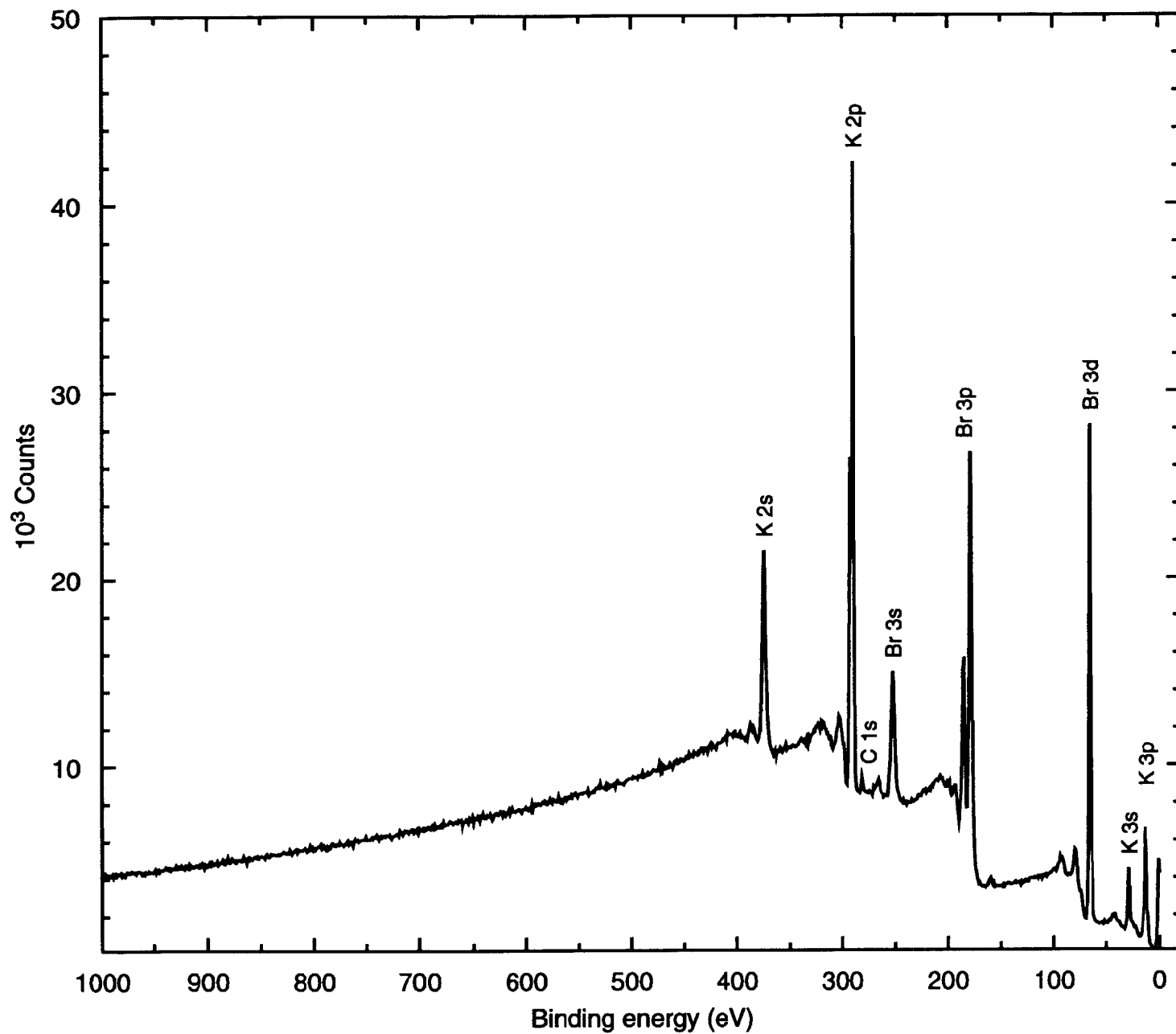
#### SPECTRAL FEATURES TABLE

Spectrum ID #	Element/Transition	Peak Energy (eV)	Peak Width FWHM (eV)	Peak Area (counts)	Sensitivity Factor	Concentration (at. %)	Peak Assignment
1	Br $3d_{5/2,3/2}$	67	...	169762	3.36	49.6	Br
1	K $2s$	377	...	100049	2.11	46.7	K
1	C $1s$	285	...	3787	1.00	3.7	C
2	Br $3d_{5/2}$	68.5	0.9	...	...	...	Br
2	Br $3d_{3/2}$	69.6	0.96	...	...	...	Br
3	K $2p_{3/2}$	293.2	1.09	...	...	...	K
3	K $2p_{1/2}$	296.0	1.07	...	...	...	K
4	C $1s$	285.0	1.68	...	...	...	C

#### ANALYZER CALIBRATION TABLE

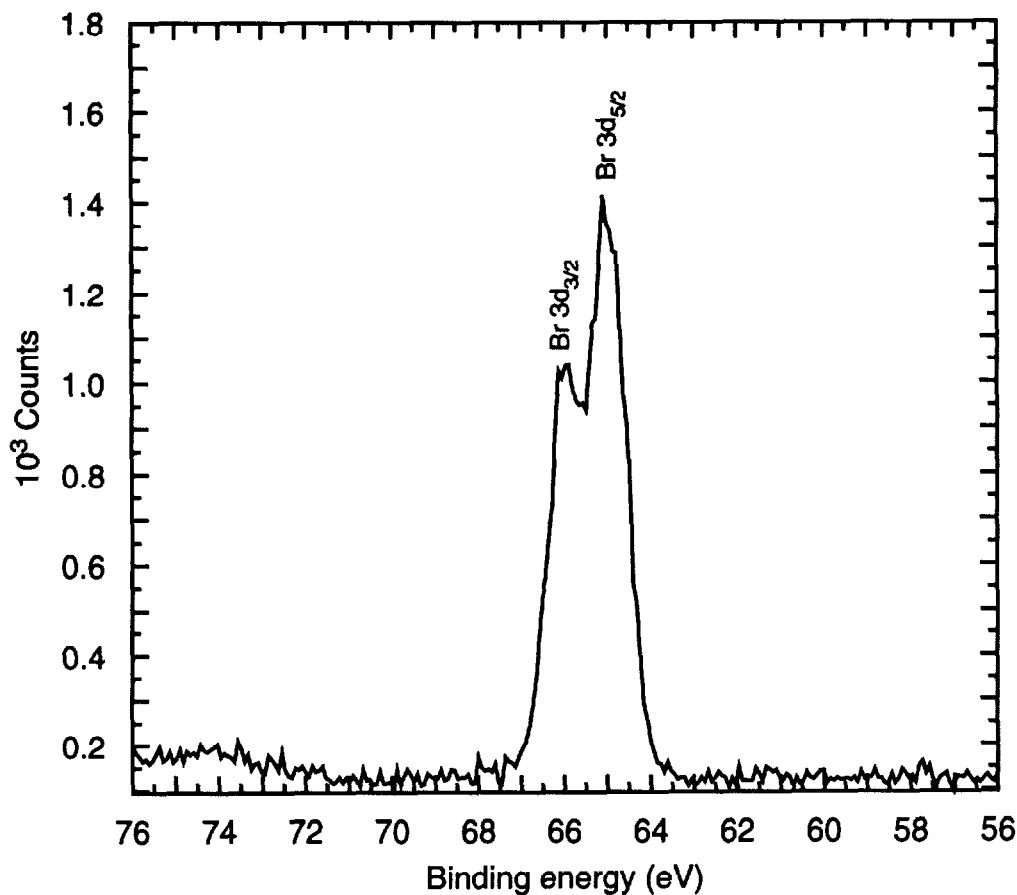
Spectrum ID #	Element/Transition	Peak Energy (eV)	Peak Width FWHM (eV)	Peak Area (counts)	Sensitivity Factor	Concentration (at. %)	Peak Assignment
...	Cu $2p_{3/2}$	$932.47 \pm 0.08$	...	...	...	...	...
...	Cu $3s$	$122.39 \pm 0.08$	...	...	...	...	...
...	Au $4f_{7/2}$	$83.96 \pm 0.08$	...	...	...	...	...
...	Au $4f_{5/2}$	$87.64 \pm 0.08$	...	...	...	...	...

**Footnote to Analyzer Calibration Table:** All of these BEs are used to calibrate the energy scale of this XPS system.

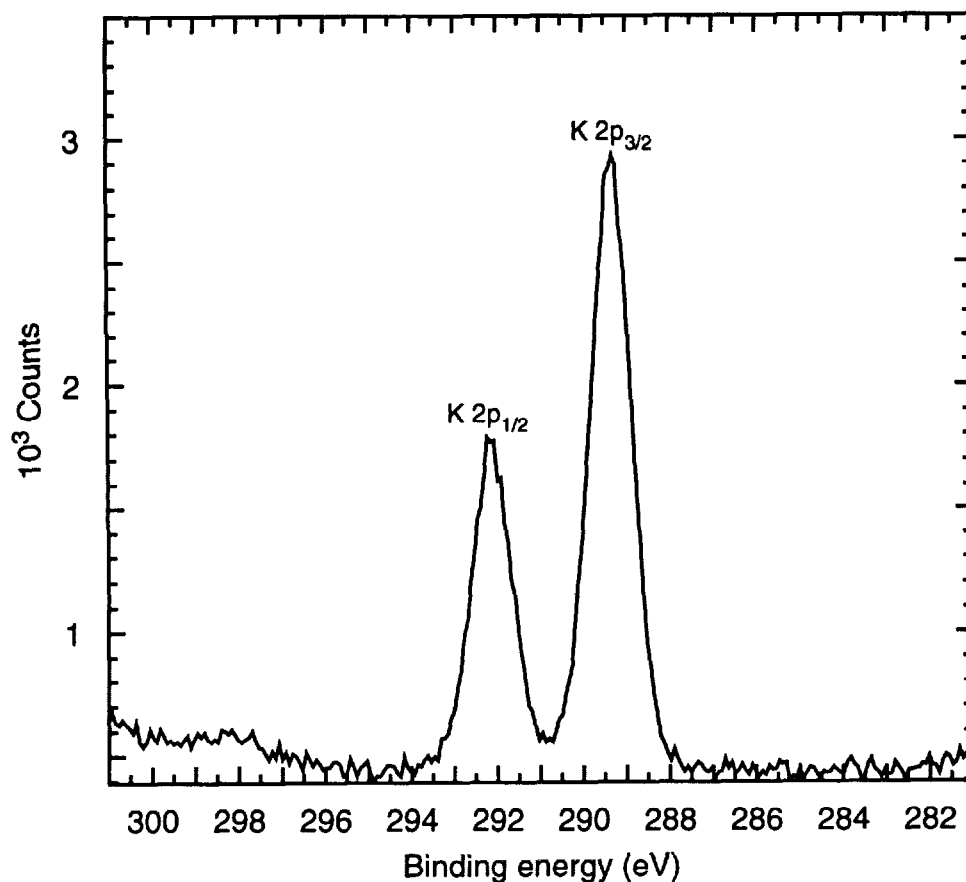


■ Accession #: 00046-01  
■ Host Material: KBr  
■ Technique: XPS  
■ Spectral Region: survey

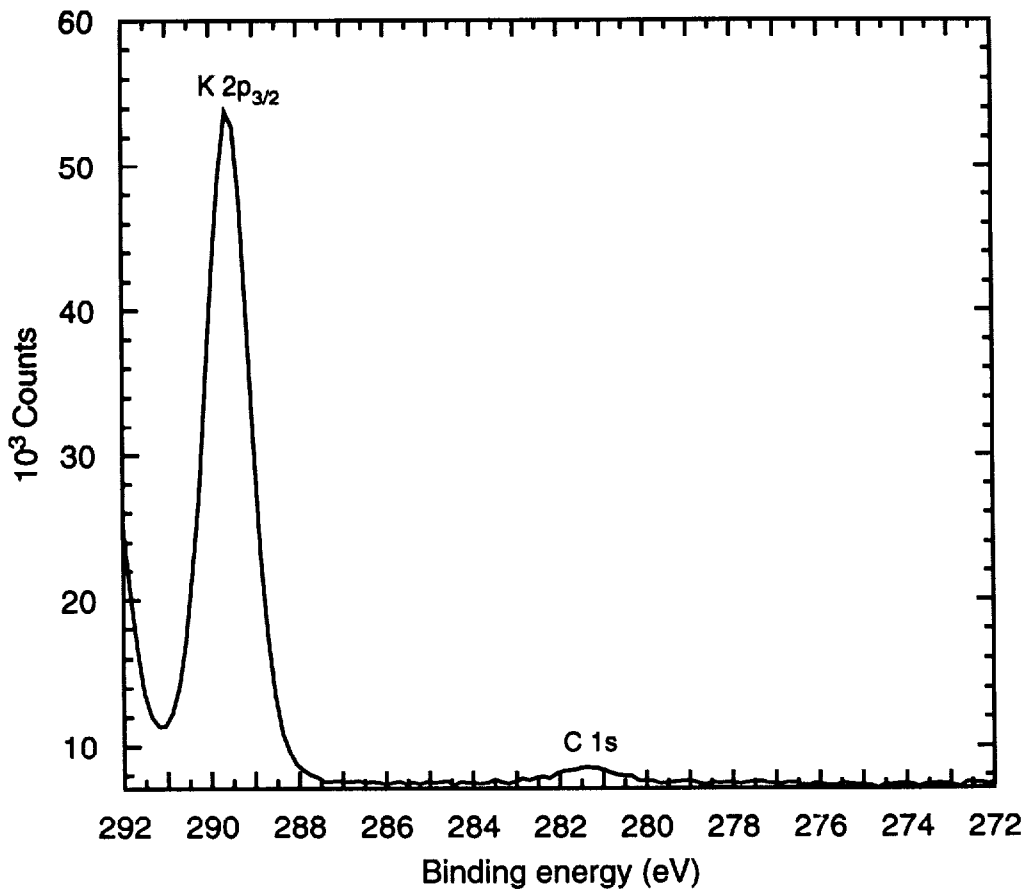
Instrument: Surface Science Instruments X-Probe 206  
Excitation Source: Al  $K_{\alpha}$  monochromatic  
Source Energy: 1486.6 eV  
Source Strength: 100 W  
Source Size: 600  $\mu\text{m}$   $\times$  600  $\mu\text{m}$   
Incident Angle: 20°  
Analyzer Type: spherical sector  
Analyzer Pass Energy: 150 eV  
Analyzer Resolution: 0.68 eV  
Emission Angle: 0°  
Data Acquisition Time: 1260 s  
Dead Time Correction: not specified  
Number of Scans: 4



■ Accession #: 00046-02  
 ■ Host Material: KBr  
 ■ Technique: XPS  
 ■ Spectral Region: Br  $3d_{5/2}$ ;  
 Br  $3d_{3/2}$   
 Instrument: Surface Science Instruments X-Probe 206  
 Excitation Source: Al  $K_{\alpha}$  monochromatic  
 Source Energy: 1486.6 eV  
 Source Strength: 10 W  
 Source Size:  $150 \mu\text{m} \times 150 \mu\text{m}$   
 Incident Angle:  $20^\circ$   
 Analyzer Type: spherical sector  
 Analyzer Pass Energy: 25 eV  
 Analyzer Resolution: 0.25 eV  
 Emission Angle:  $0^\circ$   
 Data Acquisition Time: 1020 s  
 Dead Time Correction: not specified  
 Number of Scans: 20  
 Comment: The  $3d$  signal shown here is resolved into the  $3d_{5/2}$  and  $3d_{3/2}$  transitions.



■ Accession #: 00046-03  
 ■ Host Material: KBr  
 ■ Technique: XPS  
 ■ Spectral Region: K  $2p_{3/2}$ ;  
 K  $2p_{1/2}$   
 Instrument: Surface Science Instruments X-Probe 206  
 Excitation Source: Al  $K_{\alpha}$  monochromatic  
 Source Energy: 1486.6 eV  
 Source Strength: 10 W  
 Source Size:  $150 \mu\text{m} \times 150 \mu\text{m}$   
 Incident Angle:  $20^\circ$   
 Analyzer Type: spherical sector  
 Analyzer Pass Energy: 25 eV  
 Analyzer Resolution: 0.25 eV  
 Emission Angle:  $0^\circ$   
 Data Acquisition Time: 1020 s  
 Dead Time Correction: not specified  
 Number of Scans: 20  
 Comment: The  $2p$  signal shown here is resolved into the  $2p_{3/2}$  and  $2p_{1/2}$  transitions.



■ Accession #: 00046-04  
 ■ Host Material: KBr  
 ■ Technique: XPS  
 ■ Spectral Region: C 1s; K 2p<sub>3/2</sub>  
 Instrument: Surface Science Instruments X-Probe 206  
 Excitation Source: Al K<sub>α</sub> monochromatic  
 Source Energy: 1486.6 eV  
 Source Strength: 100 W  
 Source Size: 600 μm × 600 μm  
 Incident Angle: 20°  
 Analyzer Type: spherical sector  
 Analyzer Pass Energy: 50 eV  
 Analyzer Resolution: 0.45 eV  
 Emission Angle: 0°  
 Data Acquisition Time: 260 s  
 Dead Time Correction: not specified  
 Number of Scans: 10  
 Comment: The C 1s signal is shown together with the K 2p<sub>3/2</sub> signal to assist with energy referencing.